

INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Semiconductor devices – Measurement and evaluation methods of kinetic energy harvesting devices under practical vibration environment –
Part 1: Arbitrary and random mechanical vibrations**

**Dispositifs à semiconducteurs – Méthodes de mesure et d'évaluation des dispositifs de captage d'énergie cinétique dans un environnement de vibrations concret –
Partie 1: Vibrations mécaniques arbitraires et aléatoires**





THIS PUBLICATION IS COPYRIGHT PROTECTED

Copyright © 2019 IEC, Geneva, Switzerland

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from either IEC or IEC's member National Committee in the country of the requester. If you have any questions about IEC copyright or have an enquiry about obtaining additional rights to this publication, please contact the address below or your local IEC member National Committee for further information.

Droits de reproduction réservés. Sauf indication contraire, aucune partie de cette publication ne peut être reproduite ni utilisée sous quelque forme que ce soit et par aucun procédé, électronique ou mécanique, y compris la photocopie et les microfilms, sans l'accord écrit de l'IEC ou du Comité national de l'IEC du pays du demandeur. Si vous avez des questions sur le copyright de l'IEC ou si vous désirez obtenir des droits supplémentaires sur cette publication, utilisez les coordonnées ci-après ou contactez le Comité national de l'IEC de votre pays de résidence.

IEC Central Office
3, rue de Varembé
CH-1211 Geneva 20
Switzerland

Tel.: +41 22 919 02 11
info@iec.ch
www.iec.ch

About the IEC

The International Electrotechnical Commission (IEC) is the leading global organization that prepares and publishes International Standards for all electrical, electronic and related technologies.

About IEC publications

The technical content of IEC publications is kept under constant review by the IEC. Please make sure that you have the latest edition, a corrigendum or an amendment might have been published.

IEC publications search - webstore.iec.ch/advsearchform

The advanced search enables to find IEC publications by a variety of criteria (reference number, text, technical committee,...). It also gives information on projects, replaced and withdrawn publications.

IEC Just Published - webstore.iec.ch/justpublished

Stay up to date on all new IEC publications. Just Published details all new publications released. Available online and once a month by email.

IEC Customer Service Centre - webstore.iec.ch/csc

If you wish to give us your feedback on this publication or need further assistance, please contact the Customer Service Centre: sales@iec.ch.

Electropedia - www.electropedia.org

The world's leading online dictionary on electrotechnology, containing more than 22 000 terminological entries in English and French, with equivalent terms in 16 additional languages. Also known as the International Electrotechnical Vocabulary (IEV) online.

IEC Glossary - std.iec.ch/glossary

67 000 electrotechnical terminology entries in English and French extracted from the Terms and Definitions clause of IEC publications issued since 2002. Some entries have been collected from earlier publications of IEC TC 37, 77, 86 and CISPR.

A propos de l'IEC

La Commission Electrotechnique Internationale (IEC) est la première organisation mondiale qui élabore et publie des Normes internationales pour tout ce qui a trait à l'électricité, à l'électronique et aux technologies apparentées.

A propos des publications IEC

Le contenu technique des publications IEC est constamment revu. Veuillez vous assurer que vous possédez l'édition la plus récente, un corrigendum ou amendement peut avoir été publié.

Recherche de publications IEC - webstore.iec.ch/advsearchform

La recherche avancée permet de trouver des publications IEC en utilisant différents critères (numéro de référence, texte, comité d'études,...). Elle donne aussi des informations sur les projets et les publications remplacées ou retirées.

IEC Just Published - webstore.iec.ch/justpublished

Restez informé sur les nouvelles publications IEC. Just Published détaille les nouvelles publications parues. Disponible en ligne et une fois par mois par email.

Service Clients - webstore.iec.ch/csc

Si vous désirez nous donner des commentaires sur cette publication ou si vous avez des questions contactez-nous: sales@iec.ch.

Electropedia - www.electropedia.org

Le premier dictionnaire d'électrotechnologie en ligne au monde, avec plus de 22 000 articles terminologiques en anglais et en français, ainsi que les termes équivalents dans 16 langues additionnelles. Egalement appelé Vocabulaire Electrotechnique International (IEV) en ligne.

Glossaire IEC - std.iec.ch/glossary

67 000 entrées terminologiques électrotechniques, en anglais et en français, extraites des articles Termes et Définitions des publications IEC parues depuis 2002. Plus certaines entrées antérieures extraites des publications des CE 37, 77, 86 et CISPR de l'IEC.

INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Semiconductor devices – Measurement and evaluation methods of kinetic energy harvesting devices under practical vibration environment –
Part 1: Arbitrary and random mechanical vibrations**

**Dispositifs à semiconducteurs – Méthodes de mesure et d'évaluation des dispositifs de captage d'énergie cinétique dans un environnement de vibrations concret –
Partie 1: Vibrations mécaniques arbitraires et aléatoires**

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

COMMISSION
ELECTROTECHNIQUE
INTERNATIONALE

ICS 31.080.99

ISBN 978-2-8322-6895-7

**Warning! Make sure that you obtained this publication from an authorized distributor.
Attention! Veuillez vous assurer que vous avez obtenu cette publication via un distributeur agréé.**

CONTENTS

FOREWORD	5
1 Scope	7
2 Normative references	7
3 Terms and definitions	7
4 Characteristics of kinetic energy harvesting devices	8
5 Vibration testing equipment	8
5.1 General.....	8
5.2 Vibration exciter.....	8
5.3 Mounting fixture	9
5.4 Acceleration sensor	9
5.5 Read-out circuit	9
5.6 Data recorder.....	9
6 Preparation of test bed and device	9
6.1 General.....	9
6.2 Evaluation of vibration conditions.....	9
6.3 Evaluation of electronic noise	10
7 Testing methods	10
7.1 External load.....	10
7.2 Testing time	10
7.3 Test environment	10
7.4 Measurement conditions	10
8 Measuring procedures	11
8.1 General.....	11
8.2 Single frequency response	11
8.3 Frequency sweeping response	11
8.4 Random vibration response	11
9 Test report.....	11
Annex A (informative) Example of measurement for kinetic energy harvesting device	13
A.1 General.....	13
A.2 Electret energy harvester with linear spring.....	13
A.2.1 Shape, weight and dimensions of tested energy harvesting device	13
A.2.2 Characteristics of the read-out circuit	13
A.2.3 Characteristics of the vibration exciter	14
A.2.4 Type, frequency response and accuracy of acceleration sensor	14
A.2.5 Method for fixation of the energy harvesting device on the vibration exciter	15
A.2.6 Vibration direction with respect to the gravity direction	15
A.2.7 Measurement conditions and measurement results for sinusoidal vibration	15
A.2.8 Measurement conditions and measurement results for frequency sweep	16
A.2.9 Measurement conditions and measurement results for random vibration.....	19
A.3 Inverse-magnetostrictive energy harvester with nonlinear spring	21
A.3.1 Shape, weight and dimensions of tested energy harvesting device	21
A.3.2 Characteristics of the read-out circuit	21
A.3.3 Characteristics of the vibration exciter	22
A.3.4 Type, frequency response and accuracy of acceleration sensor.....	22

A.3.5	Method for fixation of the energy harvesting device on the vibration exciter	22
A.3.6	Vibration direction with respect to the gravity direction	22
A.3.7	Measurement conditions and measurement results for sinusoidal vibration	22
A.3.8	Measurement conditions and measurement results for frequency sweep	23
A.3.9	Measurement conditions and measurement results for random vibration.....	24
A.4	Piezoelectric energy harvester with broadband response	25
A.4.1	Shape, weight and dimensions of tested energy harvesting device	25
A.4.2	Characteristics of the read-out circuit	25
A.4.3	Characteristics of the vibration exciter	26
A.4.4	Type, frequency response and accuracy of acceleration sensor.....	26
A.4.5	Method for fixation of the energy harvesting device on the vibration exciter	26
A.4.6	Vibration direction with respect to the gravity direction	27
A.4.7	Measurement conditions and measurement results for sinusoidal vibration	27
A.4.8	Measurement conditions and measurement results for frequency sweep	28
A.4.9	Measurement conditions and measurement results for random vibration.....	30
Annex B (informative)	Definition of random vibration.....	33
Bibliography	36

Figure 1 – Testing equipment for kinetic energy harvesting device for mechanical vibration.....	8
Figure A.1 – Photo of the electret energy harvester	13
Figure A.2 – Read-out circuit using voltage divider	14
Figure A.3 – Output power for sinusoidal excitation at 30,4 Hz versus the external load	15
Figure A.4 – Voltage waveforms for 30,4 Hz sinusoidal excitation at different zero-peak accelerations	16
Figure A.5 – Maximum, minimum, and RMS output voltages for frequency sweeping at different zero-to-peak accelerations	18
Figure A.6 – Output power for frequency sweeping from 15 Hz to 45 Hz at different zero-to-peak accelerations.....	19
Figure A.7 – Voltage waveforms for the random vibration with different acceleration spectral densities	20
Figure A.8 – Photo of the magnetostrictive energy harvester	21
Figure A.9 – Measurement circuit.....	21
Figure A.10 – Output power for sinusoidal excitation at 98 Hz versus the external load (zero-to-peak acceleration is 9,8 m/s ²)	23
Figure A.11 – Voltage waveforms for 116 Hz sinusoidal excitation at different zero-to-peak accelerations	23
Figure A.12 – Power spectra of the output voltage for frequency sweeping from 60 Hz to 180 Hz at different zero-to-peak accelerations	24
Figure A.13 – Voltage waveforms for the random vibration 0,49 (m/s ²) ² /Hz	24
Figure A.14 – Photo of the piezoelectric energy harvester	25
Figure A.15 – Read-out circuit using a voltage divider.....	25
Figure A.16 – Output power for 40 Hz sinusoidal excitation versus the external load (zero-to-peak acceleration is 0,98 m/s ²)	27

Figure A.17 – Voltage waveforms for 40 Hz sinusoidal excitation at different zero-to-peak accelerations	28
Figure A.18 – Voltage waveforms for frequency sweeping from 20 Hz to 60 Hz at different zero-to-peak accelerations	29
Figure A.19 – Power spectra of the output power for frequency sweeping from 20 Hz to 60 Hz at different zero-to-peak accelerations	30
Figure A.20 – Voltage waveforms for the random vibration at different acceleration spectral densities	31
Figure B.1 – Random vibration with uniform acceleration spectral density	34
Figure B.2 – Example data of random vibration	35
Table A.1 – Vibration exciter used in sinusoidal vibration	14
Table A.2 – Vibration exciter used in random vibration	14
Table A.3 – Acceleration sensor used in sinusoidal vibration	14
Table A.4 – Acceleration sensor used in random vibration	15
Table A.5 – Output voltage and power for sinusoidal excitation at the rated frequency	16
Table A.6 – Output voltage for sinusoidal excitation with frequency sweeping	18
Table A.7 – Maximum output power for frequency sweeping from 15 Hz to 45 Hz	19
Table A.8 – Peak-to-peak voltage, RMS output voltage, and mean output power for random vibration	21
Table A.9 – Vibration exciter used in sinusoidal vibration	22
Table A.10 – Acceleration sensor used in sinusoidal and random vibrations	22
Table A.11 – Output voltage and power for sinusoidal excitation at the rated frequency	23
Table A.12 – RMS output voltage and mean output power for random vibration	24
Table A.13 – Vibration exciter used in sinusoidal vibration	26
Table A.14 – Vibration exciter used in random vibration	26
Table A.15 – Acceleration sensor used in sinusoidal vibration	26
Table A.16 – Acceleration sensor used in random vibration	26
Table A.17 – Output voltage and power for sinusoidal excitation at the rated frequency	28
Table A.18 – Output voltage for sinusoidal excitation with frequency sweeping	29
Table A.19 – Maximum output power for frequency sweeping from 20 Hz to 60 Hz	30
Table A.20 – Peak-to-peak voltage, RMS output voltage, and mean output power for random vibration	32

INTERNATIONAL ELECTROTECHNICAL COMMISSION

**SEMICONDUCTOR DEVICES –
MEASUREMENT AND EVALUATION METHODS OF KINETIC
ENERGY HARVESTING DEVICES UNDER PRACTICAL
VIBRATION ENVIRONMENT –**

Part 1: Arbitrary and random mechanical vibrations

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
- 5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 63150-1 has been prepared by IEC technical committee 47: Semiconductor devices.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
47/2548/FDIS	47/2568/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 63150 series, published under the general title *Semiconductor devices – Measurement and evaluation methods of kinetic energy harvesting devices under practical vibration environment*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

IMPORTANT – The 'colour inside' logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

**SEMICONDUCTOR DEVICES –
MEASUREMENT AND EVALUATION METHODS OF KINETIC
ENERGY HARVESTING DEVICES UNDER PRACTICAL
VIBRATION ENVIRONMENT –**

Part 1: Arbitrary and random mechanical vibrations

1 Scope

This part of IEC 63150 specifies terms and definitions, and test methods for kinetic energy harvesting devices for one-dimensional mechanical vibrations to determine the characteristic parameters under a practical vibration environment. Such vibration energy harvesting devices often have their own non-linear mechanisms to efficiently capture vibration energy in a broadband frequency range.

This document is applicable to vibration energy harvesting devices with different power generation principles (such as electromagnetic, piezoelectric, electrostatic, etc.) and with different non-linear behaviour to the external mechanical excitation.

2 Normative references

There are no normative references in this document.

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

3.1

kinetic energy harvesting device

device to generate electrical energy from kinetic energy

3.2

rated frequency

frequency given in the specification

3.3

sinusoidal vibration

vibration with a sinusoidal acceleration waveform with a given frequency

3.4

random vibration

non-deterministic vibration with broadband frequency spectra with a constant root-mean-square (RMS) acceleration spectral density of which frequency range is specified

Note 1 to entry: See Annex B.